MSKSEMI















ESD

TVS

TSS

MOV

GDT

PLED

Broduct data sheet



SOT-23

Features

- 300 Watts peak pulse power (tp = $8/20\mu$ s)
- Bidirectional configurations
- Solid-state silicon-avalanche technology
- Low clamping voltage
- Low leakage current
- IEC 61000-4-2 ±30kV contact ±30kV air
- IEC 61000-4-4 (EFT) 40A (5/50ns)
- IEC 61000-4-5 (Lightning) 8A (8/20μs)

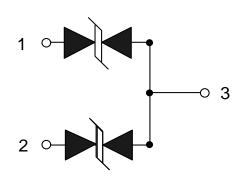
Applications

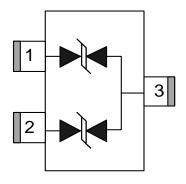
- Dataline
- Automatic Teller Machines
- Net works
- Power line

Mechanical Data

- SOT-23 package
- Molding compound flammability rating: UL 94V-0
- Packaging: Tape and Reel
- RoHS/WEEE Compliant

Schematic & PIN Configuration





SOT-23 (Top View)





Absolute Maximum Rating

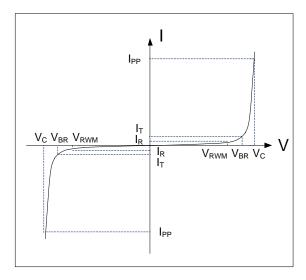
Rating	Symbol	Value	Units
Peak Pulse Power (t _p =8/20μs)	P _{PP}	300	Watts
Peak Pulse Current (t _p =8/20μs) (note1)	I_{pp}	8	A
ESD per IEC 61000-4-2 (Air) ESD per IEC 61000-4-2 (Contact)	V_{ESD}	30 30	kV
Lead Soldering Temperature	${ m T_L}$	260(10seconds)	$^{\circ}$ C
Junction Temperature	T_{J}	-55 to + 125	$^{\circ}$ C
Storage Temperature	$T_{ m stg}$	-55 to + 125	$^{\circ}$ C

Electrical Characteristics

Parameter	Symbol	Conditions	Min	Typical	Max	Units
Reverse Stand-Off Voltage	V_{RWM}				24.0	V
Reverse Breakdown Voltage	V_{BR}	$I_T=1 \text{mA}$	25.5			V
Reverse Leakage Current	I_R	V _{RWM} =24V,T=25°C		0.1	0.5	μΑ
Peak Pulse Current	I_{PP}	$t_p = 8/20 \mu s$			8	A
Clamping Voltage	V _C	$I_{PP}=8A, t_p=8/20 \mu s$		35		V
Junction Capacitance	C _j	$V_R = 0V$, $f = 1MHz$		16		pF

Electrical Parameters (TA = 25 °C unless otherwise noted)

Symbol	Parameter	
\mathbf{I}_{PP}	Maximum Reverse Peak Pulse Current	
Vc	Clamping Voltage @ Ipp	
V _{RWM}	Working Peak Reverse Voltage	
I_R	Maximum Reverse Leakage Current @ VRWM	
V_{BR}	Breakdown Voltage @ IT	
Iτ	Test Current	



Note:. $8/20\mu s$ pulse waveform.





Typical Characteristics

Figure 1: Peak Pulse Power vs. Pulse Time

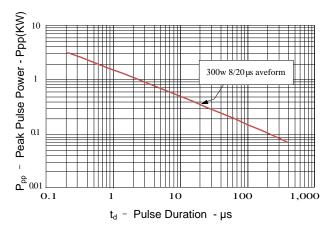


Figure 2: Power Derating Curve

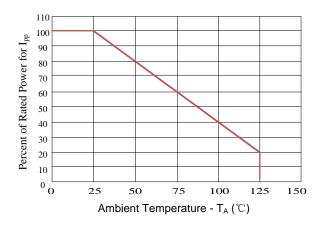


Figure3: Pulse Waveform

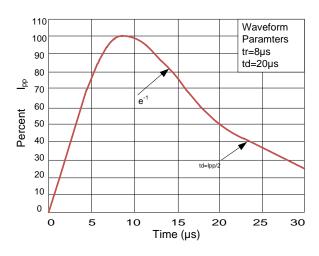
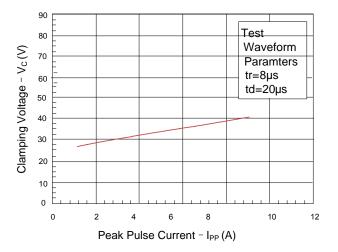
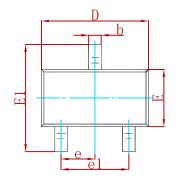


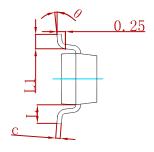
Figure 4: Clamping Voltage vs.lpp

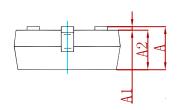


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PACKAGE MECHANICAL DATA

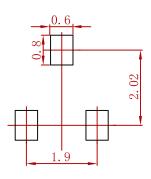






Cumbal	Dimensions In Millimeters		Dimensions In Inches	
Symbol	Min	Max	Min	Max
Α	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
С	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
E	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
е	0.950 TYP		0.037 TYP	
e1	1.800	2.000	0.071	0.079
L	0.550 REF		0.022 REF	
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

Suggested Pad Layout



- 1.Controlling dimension:in millimeters.2.General tolerance:± 0.05mm.3.The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
ESDONCAN1LT1G-MS	SOT-23	3000



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